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## Product Change Notification - JAON-19QMXF371

**Date:** 17 Feb 2015**Notification subject:** CCB 1432.01 Final Notice: Qualification of Supertex products in 8L SOIC Dual DAP and 8L SOIC Single DAP package at MMT assembly.**Notification text:**  
**PCN Status:**  
Final notification**Microchip Parts Affected:**

See attachments of affected catalog part numbers (CPN) labeled as...

PCN\_JAON-19QMXF371\_Affected\_CPN.xls

PCN\_JAON-19QMXF371\_Affected\_CPN.pdf

**Description of Change:**

Qualification of Supertex products in 8L SOIC Dual DAP and 8L SOIC Single DAP package at MMT assembly.

**Pre Change:**

Assembled at CARM

**Post Change:**

Assembled at MMT or CARM

**Impacts to Data Sheet:**

None

**Reason for Change:**

To improve productivity as part of the integration of Supertex and Microchip.

**Change Implementation Status:**

In Progress

**Estimated First Ship Date:**

March 9, 2015 (date code: 1511)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

**Markings to Distinguish Revised from Unrevised Devices:**

Traceability code

**Revision History:****July 22, 2014:** Issued initial notification.**February 17, 2015:** Issued final notification. Attached the qualification report. Updated the subject and description to include 8L SOIC Single DAP package in the scope. Revised the estimated first ship date from October 20, 2014 to March 9, 2015.**Attachment(s):**  
[PCN\\_JAON-19QMXF371\\_Qual Report.pdf](#)  
[PCN\\_JAON-19QMXF371\\_Affected\\_CPN.pdf](#)  
[PCN\\_JAON-19QMXF371\\_Affected\\_CPN.xls](#)Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.**Terms and Conditions:**If you wish to change your product/process change notification (PCN) profile please log on to our website at <http://www.microchip.com/PCN> sign into myMICROCHIP to open the myMICROCHIP home page, then select a profile option from the left navigation bar.To opt out of future offer or information emails (other than product change notification emails), click here to go to [microchipDIRECT](#) and login, then click on the "My account" link, click on "Update profile" and un-check the box that states "Future offers or information about Microchip's products or services."[Products](#) [Applications](#) [Design Support](#) [Training](#) [Sample & Buy](#) [About Us](#) [Contact Us](#)  
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**QUALIFICATION REPORT**  
**RELIABILITY LABORATORY**

**PCN #: JAON-19QMXF371**

**Date**  
**February 05, 2015**

**Qualification of Supertex products in 8L SOIC Dual DAP and  
8L SOIC Single DAP package at MMT assembly.**

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## **MICROCHIP**

### **PACKAGE QUALIFICATION REPORT**

**Purpose** Qualification of Supertex products in 8L SOIC Dual DAP and 8L SOIC Single DAP package at MMT assembly.

**CN** BC141963  
**QUAL ID** Q14188  
**MP CODE** 63001Q4CXA00  
**Part No.** TC6320TG-G  
**Lot No.** MMT-153400584.000  
**Bonding No.** BDM-000673 Rev. A  
**CCB No.** 1432.01

#### **Package**

**Type** 8L SOIC  
**Package size** 150 mils  
**Die thickness** **TPC Die:** 11 mils  
**TNC Die:** 11 mils  
**Die size** **TPC Die:** 55.10 x 55.10 mils  
**TNC Die:** 55.10 x 55.10 mils

#### **Lead Frame**

**Paddle size** 77 x 105 mils Dual DAP (ASM-Singapore)  
**Material** A194  
**Surface** Bare Cu  
**Process** Etched  
**Lead Lock** No  
**Part Number** 10100813  
**Treatment** None

#### **Die attach material**

**Epoxy (Silver paste)** 8060T (Henkel-USA)  
**Wire** Au wire (MKE-Korea)  
**Mold Compound** G600V (Sumitomo-Japan)  
**Plating Composition** Matte Tin



## MICROCHIP PACKAGE QUALIFICATION REPORT

### Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
MMT-153400584.000	TMPE215024567.100	1447JQ9
	TMPE215014304.211	

### Result

☒ Pass ☐ Fail ☐ \_\_\_\_\_

8L SOIC (.150") assembled by MMT pass reliability test per Supertex standard qual plan for SMD Package. This package was qualified the Moisture/Reflow Sensitivity Classification Level 1 at 260°C reflow temperature per IPC/JEDEC J-STD-020D standard.

**Note:** Risk release qual report due to THB is on going

Prepared By: Wittawat P. Date: February 05, 2015 (Reliability Engineer)

(Mr. Wittawat Premniwat)

Approved By: Somnuek Date: February 05, 2015 (Reliability Manager)

(Mr. Somnuek Thongprasert)

## PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard / Method	Qty. (Acc.)	Def/SS	Result	Remarks
<b>Moisture/Reflow Sensitivity Classification Test (At MSL Level 1)</b>	85°C/ 85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243  ( IPC/JEDEC J-STD-020D)	IPC/JED EC J- STD- 020D	25	0/25	Pass	

<b><u>Precondition Prior Perform Reliability Tests</u> (At MSL Level 1)</b>	Bake 150°C, 24 hrs System: CHINEE			250		
	85°C/85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH			250		
	3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243			250		
	<b>Electrical Test</b> : Post test Supertex Hongkong			0/250	Pass	

# PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
<b>TEST 1: ASSEMBLY PROCESS CHARACTERIZATION</b>						
<b>1a. Die Shear</b>	Die Shear (Minimum: 2.5 kgf)	MIL-STD-883J-M2019.8	5(0)	0/5 0/5	Pass	
<b>11a. D/A Bondline Thicknes</b>	Epoxy Cured BLT (Dry) Control 0.6~0.9 mil	Per assembly site Specs	5(0)	0/5	Pass	
<b>1b. Bond Shear</b>	Bond Shear (Minimum: 18.00 grams)	JESD22-B116A	30 (0) Wires	0/30	Pass	
<b>1c. Wire Bond Pull</b>	Wire Pull (Minimum: 4.0 grams)	MIL-STD-883J-M2011.9 Condition C or D	30 (0) Wires	0/30	Pass	
<b>1d.X-ray</b>	N/A	X-Ray	2 (0)	0/2	Pass	
<b>1e. Terminal Plating Thickness</b>	N/A	XRF or else	5 (0)	0/5 Units	Pass	
<b>1f. Terminal Plating /Solder Ball Material</b>	N/A	XRF,RoHS report or else	5 (0)	0/5 Units	Pass	
<b>TEST 2: FINAL TEST</b>						
<b>Post-Assembly Final Test Yield</b>	Per device spec  Electrical Test: Supertex HK	Per device spec  >85% test yield	1000	4/996	Pass	Test Location: Supertex Hongkong

# PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
<b>TEST 3: PACKAGE INTEGRITY AND MECHANICAL TEST</b>						
<b>3a. Visual Examination</b>	<b>Stress Condition:</b> Supertex spec#QCGP-1001	Supertex spec#QCG P-1001	315(0)	0/315	Pass	Test Location: Supertex Hongkong
<b>3b. Physical Dimension</b>	<b>Stress Condition:</b> Post Assembly	JESD22- B100B	8(0)	0/8	Pass	Test Location: Supertex Hongkong
<b>3c. Solderability (Tin-alloy)</b>	<b>Stress Condition:</b> 1) Condition C (Tin-alloy):8 hrs. Steam age; 2) Test Method 1:Dip&Look Test; Group 1:Test to SnPb solder (215+/-5 C); Group 2:Test to Pb-free solder (245+/-5C);	JESD22- B102E	8(0) 8(0)	0/8 0/8	Pass Pass	Test Location: Supertex Hongkong

# PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
<b>TEST 4: PACKAGE INTEGRITY AND MECHANICAL TEST</b>						
<b>4a. Precondition Prior Perform Reliability Tests (At MSL Level 1)</b>	<b>Stress Condition:</b> -Bake 150°C, 24 hrs System: CHINEE -85°C/85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH -3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243 Electrical Test: Post test at Supertex HK	JESD22-A113F	250(0)	0/250	Pass	Test Location: Reliability MTAI
<b>4b. Auto Clave</b>	<b>Stress Condition:</b> 1) for SMD,MSL pre-conditioned prior to test 2) 121C/100%RH / 15PSIG / 168 hrs Electrical Test: Post test at Supertex HK	JESD22-A102D	45 (0)	0/45	Pass	Test Location: Supertex Hongkong
<b>4c. Thermal Shock</b>	<b>Stress Condition:</b> 1) for SMD,MSL pre-conditioned prior to test 2) Cond B:-55 to 125C / 200 cyc Electrical Test: Post test at Supertex HK	MIL-STD-883HM1011.9	50(0)	0/50	Pass	Test Location: MMT
<b>4d. Temperature Cycling</b>	<b>Stress Condition:</b> 1) for SMD,MSL pre-conditioned prior to test 2) Cond C:-65 to 150C / 500 cyc Electrical Test: Post test at Supertex HK	MIL-STD-883HM1010.8	50(0)	0/50	Pass	Test Location: Reliability MTAI
<b>4e. Temperature Humidity Bias (THB)</b>	<b>Stress Condition:</b> 1) for SMD,MSL pre-conditioned prior to test 2) biased @ 85C / 85%RH for 168 / 500 1000 hrs (for Engineering Info only) Electrical Test: Post test at Supertex HK	JESD22-A101C	45(0)	-	On going	Test Location: Supertex Sunnyvale USA



PCN_JAON-19QMXF371
CATALOG PART NBR
TC1550TG-G
TC2320TG-G
TC6215TG-G
TC6320TG-G
TC6320TG-G-D607
TC6320TG-G-D626
TD9944TG-G
TD9944TG-G-D590
TN2640LG-G
TP2640LG-G